Application/Control No. Applicant(s)/Patent Under Reexamination 09/940,810 ITOU ET AL Notice of References Cited Examiner Art Unit Page 1 of 1 A. Sefer 2826 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-2001/0004296 06-2001 Van Aerle et al. 359/254 Α В US-US-С US-D US-Ε F US-US-G Н US-US-1 J US-US-Κ L US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY JP 2000-206333 07-2000 Shimadad Ν Japan 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) ٧ W

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.